

## Supporting Information for

### **Interlayer engineering of MoS<sub>2</sub> nanosheets for high-rate potassium-ion storage**

Wei Kang<sup>1</sup>, Yuchen Wang<sup>1</sup>, and Cuihua An<sup>1,2\*</sup>

<sup>1</sup>Tianjin Key Laboratory of Advanced Functional Porous Materials, Institute for New Energy Material & Low-Carbon Technologies, School of Materials Science and Engineering, Tianjin University of Technology, Tianjin 300384, P.R. China

<sup>2</sup>Key Laboratory of Advanced Energy Materials Chemistry (Ministry of Education), College of Chemistry, Nankai University, Tianjin 300071, P.R. China

\*Corresponding Author E-mail Address [ancuihua@tjut.edu.cn]

$$i = av^b \quad 1$$

Where  $i$  is the peak current,  $v$  is the scan rate, and  $a$  and  $b$  are the parameters. The value of  $b$  is calculated from the  $\log(i) - \log(v)$  curve to determine the electrochemical behavior.  $b = 1$  represents the pseudocapacitance control process,  $b = 0.5$  represents the diffusion control process.

$$i(v) = k_1v + k_2v^{1/2} \quad 2$$

Where  $i$  is the peak current and  $v$  is the scan rate.  $k_1v$  and  $k_2v^{1/2}$  represent the capacitive control process and diffusion control process. To obtain the values of the parameters  $k_1$  and  $k_2$ , we draw  $i/v^{1/2}$  and  $v^{1/2}$ , where  $k_1$  and  $k_2$  can be determined by the slope on the straight line and the y-axis intercept point.

$$D = \frac{4}{\pi\tau} \left( \frac{m_B V_M}{M_B S} \right)^2 \left( \frac{\Delta E_S}{\Delta E_t} \right)^2 \quad 3$$

Where  $\tau$  is the relaxation time;  $m_B$  is the mass of the electrode active material;  $V_M$  is the molar volume of the electrode material;  $M_B$  the molar mass of the electrode active material;  $S$  is the area of the electrode;  $\Delta E_S$  is the voltage change due to the pulse;  $\Delta E_t$  is the constant current charge (discharge) voltage variation of the electricity.

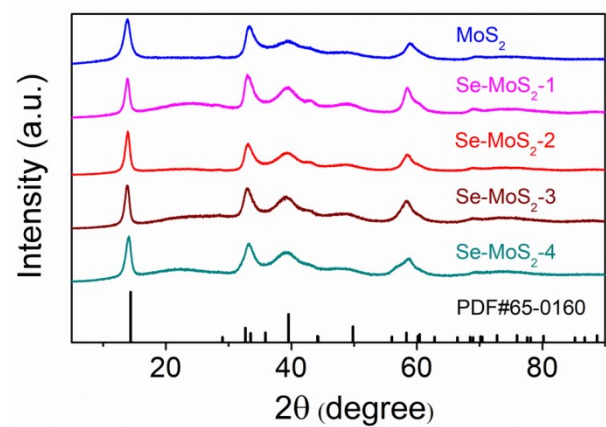


Fig. S1 XRD patterns for all the samples.

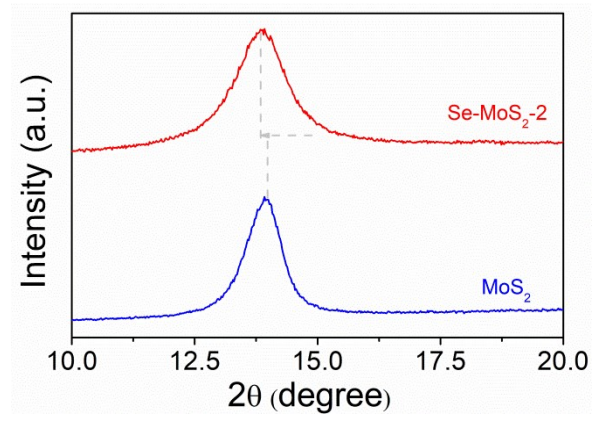


Fig. S2 XRD patterns for MoS<sub>2</sub> and Se-MoS<sub>2</sub>-2.

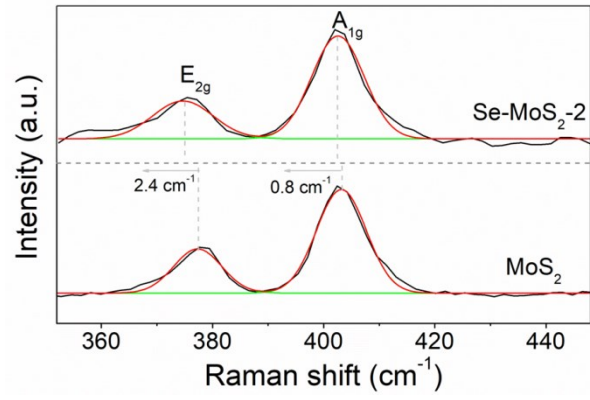


Fig. S3 Raman spectrum for MoS<sub>2</sub> and Se-MoS<sub>2</sub>-2.

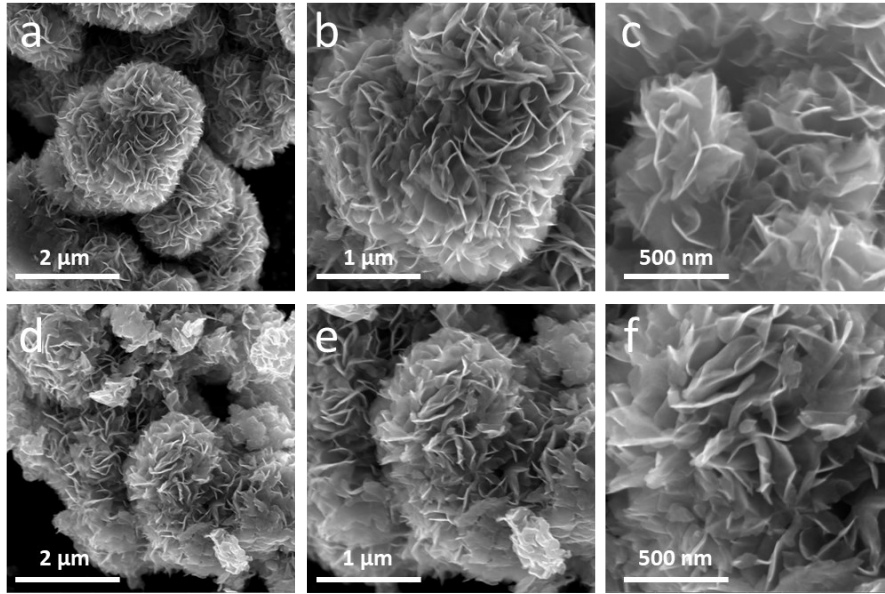


Fig. S4 (a-c) SEM for MoS<sub>2</sub>; (d-e) SEM for Se-MoS<sub>2</sub>-2.

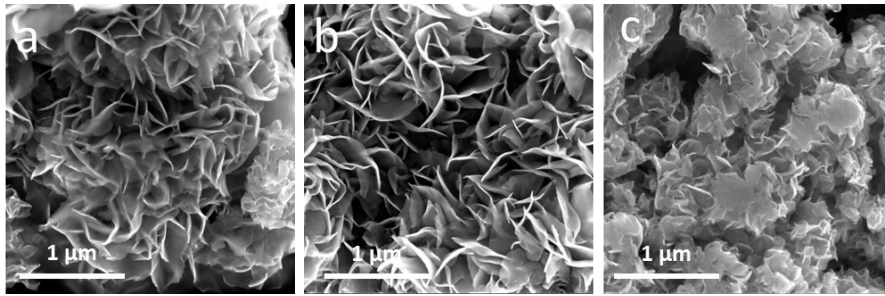


Fig. S5 (a) SEM for Se-MoS<sub>2</sub>-1; (b) SEM for Se-MoS<sub>2</sub>-3; (c) SEM for Se-MoS<sub>2</sub>-4.

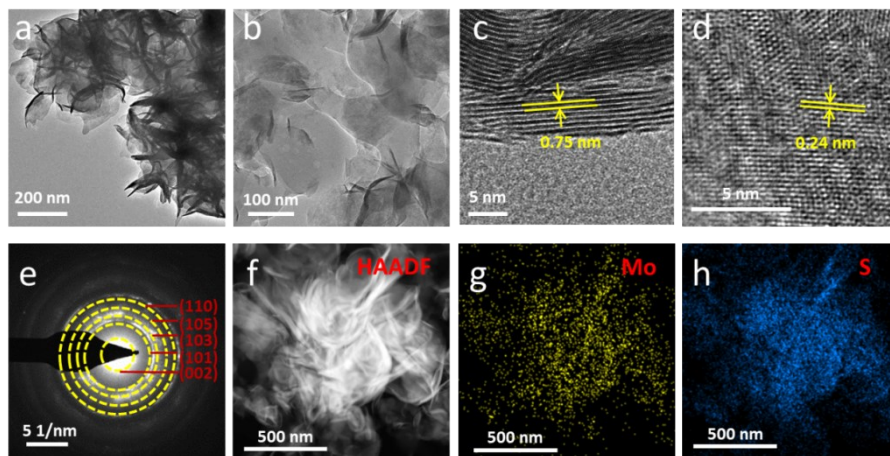


Fig. S6 (a,b) TEM images; (c,d) HRTEM images; (e) SAED pattern; (f-h) HAAADF-STEM and elemental mapping images for MoS<sub>2</sub>.



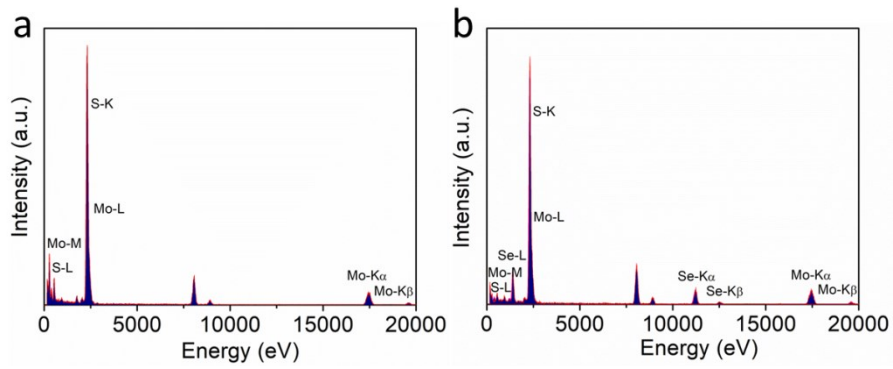


Fig. S7 (a) Energy spectrum for MoS<sub>2</sub>; (b) Energy spectrum for Se-MoS<sub>2</sub>-2.

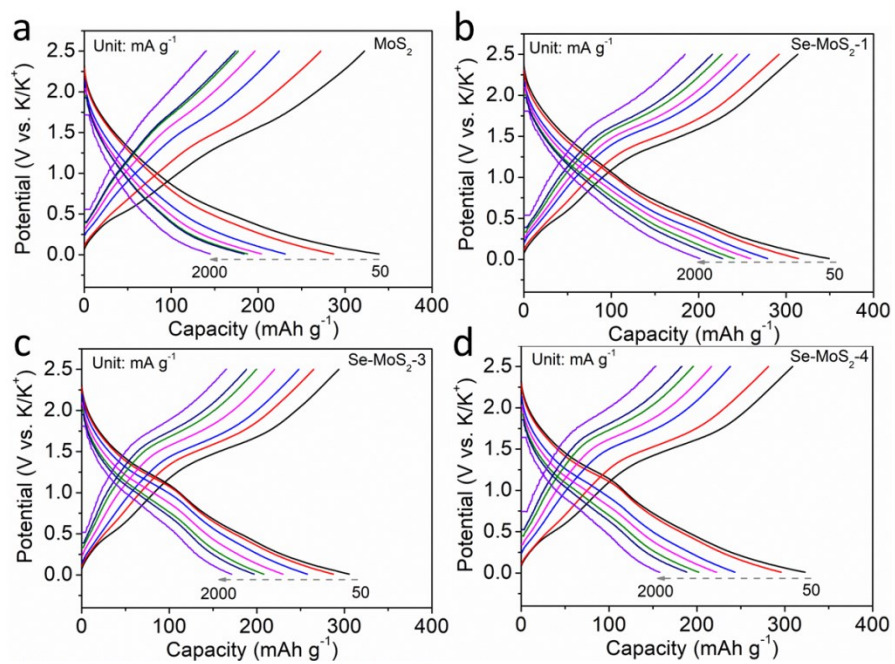


Fig. S8 Charge/discharge curves at 50 to 2000 mA g<sup>-1</sup> (a) for MoS<sub>2</sub>; (b) for Se-MoS<sub>2</sub>-1; (c) for Se-MoS<sub>2</sub>-3; (d) for Se-MoS<sub>2</sub>-4.

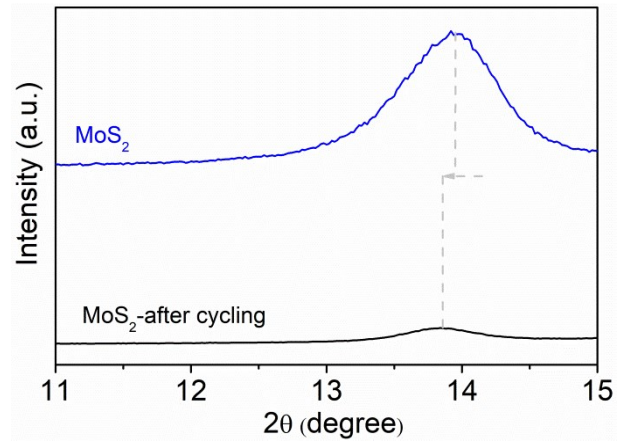


Fig. S9 XRD patterns of MoS<sub>2</sub> and MoS<sub>2</sub> after cycling.

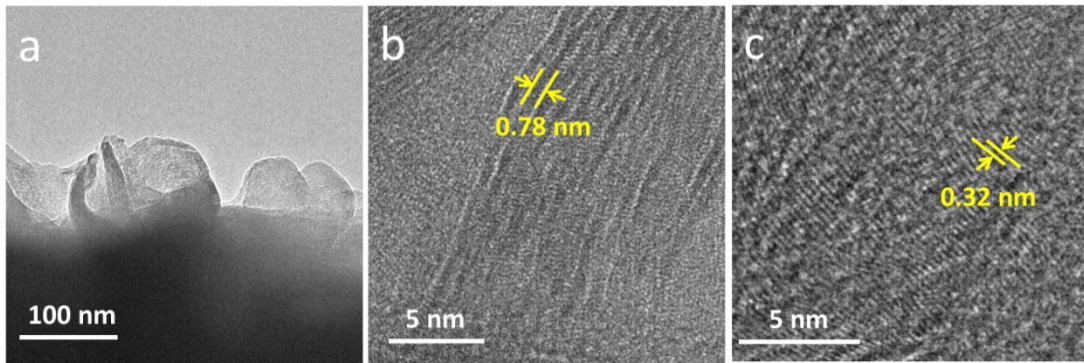


Fig. S10 HRTEM images for MoS<sub>2</sub> after cycling.

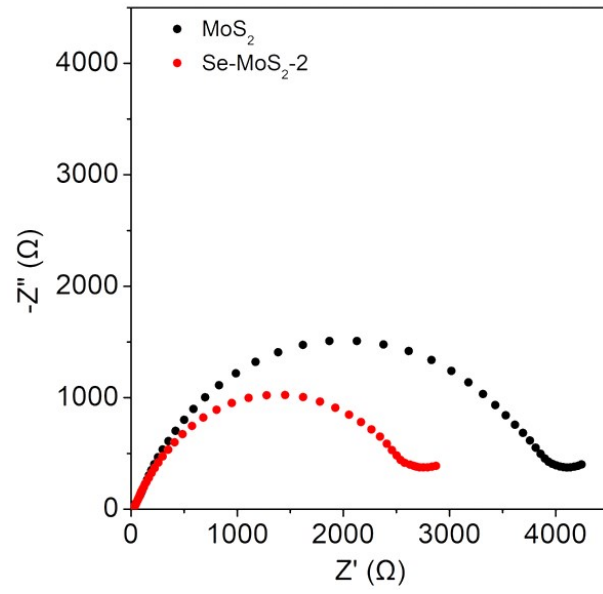


Fig. S11 The Nyquist plots for  $\text{MoS}_2$  and  $\text{Se-MoS}_2\text{-2}$  after 1000 cycles.

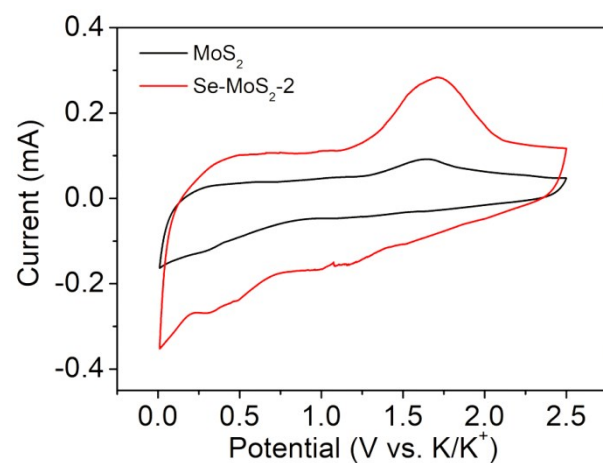


Fig. S12 CV curves of MoS<sub>2</sub> and Se-MoS<sub>2</sub>-2 at 0.2 mV s<sup>-1</sup>.

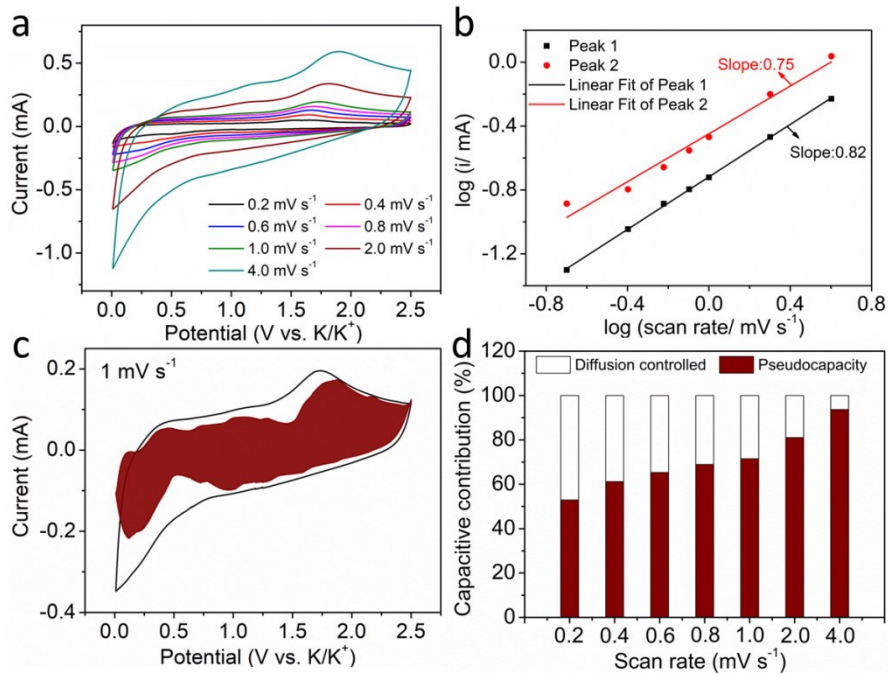


Fig. S13 (a) CV curves of MoS<sub>2</sub> at scan rates from 0.2 to 4 mV s<sup>-1</sup>; (b) the relationship peak current and scan rates; (c) the total and capacitive current responses at a 1 mV s<sup>-1</sup> are the area enclosed by black lines and the shaded region;(d) The percentages of capacitive contributions at different scan rates.

Table S1 Comparison of the potassium storage performance of Se-MoS<sub>2</sub>-2 in this work with the rate performance of previously reported materials

<b>Anode materials</b>	<b>Current density: mA g<sup>-1</sup></b>	<b>Capacity: mAh g<sup>-1</sup></b>	<b>Reference</b>
Se-MoS <sub>2</sub>	From 50 to 2000	From 642 to 212	This work
Fe <sub>9</sub> S <sub>10</sub> @MoS <sub>2</sub> @C	From 500 to 2000	Form 288 to 205	1
MoS <sub>2</sub> /N-doped-C	From 100 to 2000	From 258 to 131	2
MoSe <sub>2</sub> /N-C	From 100 to 2000	From 300 to 178	3
MoO <sub>2</sub> /rGO	From 50 to 500	From 281.8 to 176.4	4
MoS <sub>2</sub> @rGO	From 100 to 2000	From 364.8 to 196.8	5
MoS <sub>2</sub> @SnO <sub>2</sub> @C	From 50 to 2000	From 595 to 168	6
EF-Ta <sub>2</sub> NiSe <sub>5</sub>	From 50 to 2000	From 308 to 62	7



## Reference

1. C. Zhang, F. Han, F. Wang, Q. Liu, D. Zhou, F. Zhang, S. Xu, C. Fan, X. Li and J. Liu, *Energy Storage Mater.*, 2020, **24**, 208-219.
2. B. Jia, Q. Yu, Y. Zhao, M. Qin, W. Wang, Z. Liu, C.-Y. Lao, Y. Liu, Z. Zhang and X. Qu, *Adv. Funct. Mater.*, 2018, **28**, 1803409.
3. J. Ge, L. Fan, J. Wang, Q. Zhang, Z. Liu, E. Zhang, Q. Liu, X. Yu and B. Lu, *Adv. Energy Mater.*, 2018, **8**, 1801477.
4. C. Liu, S. Luo, H. Huang, Y. Zhai and Z. Wang, *ChemSusChem*, 2019, **12**, 873-880.
5. S. Chong, L. Sun, C. Shu, S. Guo, Y. Liu, W. A. Wang and H. K. Liu, *Nano Energy*, 2019, **63**, UNSP 103868.
6. Z. Chen, D. Yin and M. Zhang, *Small* 2018, **14**, 1703818.
7. H. Tian, X. Yu, H. Shao, L. Dong, Y. Chen, X. Fang, C. Wang, W. Han and G. Wang, *Adv. Energy Mater.*, 2019, **9**, 1901560.